

Title (en)

X-ray optical system with aperture in the focus of a X-ray mirror

Title (de)

Röntgen-optisches System mit Blende im Fokus eines Röntgen-Spiegels

Title (fr)

Système optique à rayons X avec ouverture dans le focus d'un miroir à rayons X

Publication

**EP 1324351 A3 20070718 (DE)**

Application

**EP 02027472 A 20021210**

Priority

DE 10162093 A 20011218

Abstract (en)

[origin: EP1324351A2] The system has a first graded multilayered mirror (A) an X-ray source which is positioned such that the extension of X-ray radiation (Qx) in X-axis, is larger than the region of acceptance of the mirror along X-axis. A collimator is positioned between the X-ray source and the mirror such that the distance between the collimator and the source satisfies preset relation including angle subtended by the mirror along X-axis. <??>Independent claims are also included for the following: <??>(1) X-ray spectrometer; <??>(2) X-ray diffractometer; and <??>(3) X-ray microscope.

IPC 8 full level

**G21K 1/06** (2006.01)

CPC (source: EP US)

**G21K 1/06** (2013.01 - EP US)

Citation (search report)

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Designated contracting state (EPC)

AT BE BG CH CY CZ DE DK EE ES FI FR GB GR IE IT LI LU MC NL PT SE SI SK TR

Designated extension state (EPC)

AL LT LV MK RO

DOCDB simple family (publication)

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DOCDB simple family (application)

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